

<b>Notice of References Cited</b>	Application/Control No. 10/577,325		Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
	Examiner MATTHEW W. SUCH		Art Unit 2891	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,224,787	05-2001	Hanna et al.	252/299.3
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Klauk, H., et al. "Contact Resistance in Organic Thin Film Transistors." SOLID-STATE ELECTRONICS, Vol. 47 (2003): pp. 297-301.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.